

FORM PTO-1449
(REV. 7-80)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.

SERIAL NO.

TI-14124D.3

101649,274
div. of 09/597,472

LIST OF DOCUMENTS CITED BY APPLICANT

(Use several sheets if necessary)

APPLICANT

Lee D. Whetsel

FILING DATE

August 27, 2003

GROUP

TBD 2133

U.S. PATENT DOCUMENTS

+EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
CB	Re. 31,056	10/12/1982	Chau, et al.	324	73 R	5/28/1980
	3,739,193	6/12/1973	Pryor	307	205	1/11/1971
	3,789,359	1/29/1974	Clark, Jr., et al.	340	146.1D	10/4/1972
	3,824,678	7/23/1974	Harris, et al.	29	578	8/31/1970
	3,831,149	8/20/1974	Job	340	172.5	2/14/1973
	3,838,264	9/24/1974	Maker	235	153 AM	11/23/1971
	3,873,818	3/25/1975	Barnard	253	153 AC	10/29/1973
	3,976,940	8/24/1976	Chau, et al.	324	73 R	2/25/1975
	4,023,142	5/10/1977	Woessner	340	172.5	4/14/1975
	4,066,882	1/3/1978	Esposito	235	302	8/16/1976
	4,086,375	4/25/1978	LaChapelle, Jr., et al.	427	90	11/7/1975
	4,092,733	5/30/1978	Coontz, et al.	365	200	5/7/1976
	4,108,359	8/22/1978	Proto	235	304	3/30/1977
	4,146,835	3/27/1979	Chnapko, et al.	324	73 R	3/8/1978
	4,161,276	7/17/1979	Sacher, t al.	235	302	3/1/1978
	4,216,539	8/5/1980	Raymond, et al.	371	20	5/5/1978
	4,242,751	12/30/1980	Henckels, et al.	371	26	2/24/1976
	4,264,807	4/28/1981	Moen, et al.	235	92 GD	4/9/1979
	4,268,902	5/19/1981	Berglund, et al.	364	200	10/23/1978
	4,286,173	8/25/1981	Oka, et al.	307	440	3/27/1978
	4,308,616	12/29/1981	Timoc	371	23	5/29/1979
	4,309,767	1/5/1982	Andow, et al.	371	24	8/21/1979
	4,312,066	1/19/1982	Bantz, et al.	371	16	12/28/1979
	4,339,710	7/13/1982	Hapke	324	73 R	2/12/1979
	4,357,703	11/2/1982	Van Brunt	371	15	10/9/1980
	4,365,334	12/21/1982	Smith, et al.	371	27	2/9/1981
	4,366,478	12/28/1982	Masuda, et al.	340	825	1/5/1981
	4,390,969	6/1/1983	Hayes	395	550	4/21/1980
	4,426,697	1/1/1984	Petersen, et al.	340	825.52	1/24/1981
	4,439,858	3/1/1984	Petersen	371	20	5/28/1981
	4,483,002	11/13/1984	Groom, Jr., et al.	371	29	4/19/1982
	4,488,259	12/11/1984	Mercy	364	900	10/29/1982
	4,493,077	1/8/1985	Agrawal, et al.	371	25	9/9/1982
CB	4,494,066	1/15/1985	Goel, et al.	324	73 R	7/2/1981

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+EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
CB	4,498,172	2/5/1985	Bhavsar	371	25	7/26/1982
	4,503,536	3/5/1985	Panzer	371	25	9/16/1982
	4,504,784	3/12/1985	Goel, et al.	324	73R	7/2/1981
	4,513,373	4/1/1985	Sheets	364	200	12/28/1982
	4,513,418	4/23/1985	Bardell, Jr, et al.	371	25	11/8/1982
	4,514,845	4/30/1985	Starr	371	15	8/23/1982
	4,519,078	5/21/1985	Komonytshy	371	25	9/29/1982
	4,553,090	11/12/1985	Hatano, et al.	324	73 AT	7/23/1980
	4,575,674	3/11/1986	Bass, et al.	324	73 R	7/1/1983
	4,587,609	5/1/1986	Boudreau, et al.	395	726	7/1/1983
	4,594,711	6/10/1986	Thatte	371	25	11/10/1983
	4,597,042	6/24/1986	d'Angeac	364	200	9/13/1983
	4,597,080	6/24/1986	Thatte, et al.	371	25	11/14/1983
	4,598,401	7/1/1986	Whelan	371	25	6/25/1984
	4,601,034	7/15/1986	Sridhar	371	25	3/30/1984
	4,602,210	7/22/1986	Fasang, et al.	324	73	12/28/1984
	4,612,499	9/16/1986	Andresen, et al.	324	73 R	11/7/1983
	4,615,029	9/30/1986	Hu, et al.	370	89	12/3/1984
	4,618,956	10/21/1986	Horst	371	68	9/29/1983
	4,621,363	11/4/1986	Blum	371	25	12/6/1984
	4,627,018	12/1/1986	Trost, et al.	395	476	9/8/1983
	4,628,511	12/9/1986	Stitzlein, et al.	371	22	2/25/1982
	4,635,193	1/6/1987	Moyer, et al.	364	200	6/27/1984
	4,635,261	1/6/1987	Anderson, et al.	371	25	1/26/1985
	4,638,313	1/20/1987	Sherwood, et al.	340	825.52	11/8/1984
	4,646,298	2/1/1987	Laws, et al.	371	16	5/1/1984
	4,651,088	3/17/1987	Sawada	324	73R	5/6/1985
	4,669,061	5/26/1987	Bhavsar	365	154	12/21/1984
	4,672,307	6/9/1987	Breuer, et al.	324	73 R	12/20/1985
	4,674,089	6/16/1987	Poret, et al.	371	25	4/16/1985
	4,679,192	7/1/1987	Vanbrabant	340	825.52	1/24/1986
	4,680,539	7/14/1987	Tsai	324	73	12/30/1983
	4,680,733	7/14/1987	Duforestel	364	900	10/29/1984
	4,687,988	8/18/1987	Eichelberger, et al.	324	73 AT	6/24/1985
CB	4,694,293	9/15/1987	Sugiyama, et al.	340	825.68	9/16/1985

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+EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
CB	4,698,588	10/6/1987	Hwang, et al.	324	73 R	10/23/1985
	4,701,916	10/20/1987	Naven, et al.	371	15	3/17/1986
	4,701,921	10/20/1987	Powell, et al.	371	25	10/23/1985
	4,710,931	12/1/1987	Bellay, et al.	371	25	10/23/1985
	4,710,933	12/1/1987	Powell, et al.	371	25	10/23/1985
	4,734,921	3/29/1988	Giangano, et al.	377	72	11/25/1986
	4,740,970	4/26/1988	Burrows, et al.	371	15	12/11/1985
	4,743,841	5/10/1988	Takeuchi	324	73 R	5/20/1985
	4,745,355	5/17/1988	Eichelberger, et al.	324	73 R	5/11/1987
	4,759,019	7/19/1988	Bentley, et al.	371	3	7/10/1986
	4,763,066	8/9/1988	Yeung, et al.	324	73R	7/23/1986
	4,764,926	8/16/1988	Knight, et al.	371	25	12/11/1985
	4,777,616	10/11/1988	Moore, et al.	364	900	5/12/1986
	4,783,785	11/8/1988	Hanta	371	25	1/5/1987
	4,788,683	11/29/1988	Hester, et al.	371	20	1/14/1986
	4,791,358	12/13/1988	Sauerwald, et al.	324	73 R	9/2/1986
	4,799,004	1/17/1989	Mori	324	73 R	1/25/1988
	4,799,052	1/1/1989	Near, et al.	340	825.52	1/13/1986
	4,800,418	1/24/1989	Natsui	357	68	9/6/1984
	4,801,870	1/31/1989	Eichelberger, et al.	324	73R	6/24/1985
	4,802,163	1/31/1989	Hirabayshi	371	15	12/29/1986
	4,808,844	2/28/1989	Ozaki, et al.	307	243	4/17/1986
	4,811,299	3/7/1989	Miyazawa, et al.	365	201	4/22/1987
	4,812,678	3/14/1989	Abe	307	443	3/23/1987
	4,817,093	3/28/1989	Jacobs, et al.	371	25	6/18/1987
	4,819,234	4/4/1989	Huber	371	19	5/1/1987
	4,821,269	4/11/1989	Jackson, et al.	371	16	10/23/1986
	4,825,439	4/25/1989	Sakashita, et al.	371	15	8/18/1987
	4,833,395	5/23/1989	Sasaki, et al.	324	73 R	10/23/1987
	4,833,676	5/23/1989	Koo	371	15	7/30/1987
	4,855,954	8/8/1989	Turner, et al.	365	185	3/4/1985
	4,857,835	8/15/1989	Whetsel, Jr.	324	73	11/5/1987
	4,860,288	8/22/1989	Teske, et al.	371	1	10/23/1987
	4,860,290	8/22/1989	Daniels, et al.	371	25	6/2/1987
CB	4,862,071	8/29/1989	Sato, et al.	324	73 R	11/18/1988

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FORM PTO-1449 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. TI-14124D.3	SERIAL NO. 10/649274 div. of 09/597,478 CB		
LIST OF DOCUMENTS CITED BY APPLICANT <i>(Use several sheets if necessary)</i>				APPLICANT Lee D. Whetsel			
				FILING DATE August 27, 2003	GROUP TBD 2133		
U.S. PATENT DOCUMENTS							
+EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)	
CB	4,862,072	8/29/1989	Harris, et al.	324	73 R	9/8/1988	
	4,864,579	9/5/1989	Kishida, et al.	371	22.3	8/3/1987	
	4,866,508	9/12/1989	Eichelberger, et al.	357	74	9/26/1986	
	4,870,345	9/26/1989	Tomioka, et al.	371	22.3	8/3/1987	
	4,872,169	10/3/1989	Whetsel, Jr.	371	22.3	3/6/1987	
	4,875,003	10/17/1989	Burke	324	73 R	2/21/1989	
	4,878,168	10/31/1989	Johnson, et al.	364	200	10/29/1986	
	4,879,717	11/7/1989	Sauerwald, et al.	371	22.3	9/2/1988	
	4,887,262	12/12/1989	van Veldhuizen	370	85.1	3/15/1988	
	4,887,267	12/12/1989	Kanuma	371	22.3	12/28/1987	
	4,893,072	1/9/1990	Matsumoto	371	223	6/22/1988	
	4,894,830	1/16/1990	Kawai	371	22.3	1/19/1988	
	4,896,262	1/23/1990	Wayama, et al.	364	200	2/22/1985	
	4,899,273	2/6/1990	Omoda, et al.	364	200	12/10/1986	
	4,903,266	2/20/1990	Hack	371	21.2	4/29/1988	
	4,910,735	3/20/1990	Yamashita	371	22.4	12/17/1987	
	4,912,633	3/27/1990	Schweizer, et al.	364	200	10/24/1988	
	4,912,709	3/27/1990	Teske, et al.	371	22.1	10/23/1987	
	4,918,379	4/17/1990	Jongepier	324	73.1	8/31/1988	
	4,926,425	5/15/1990	Hedtke, et al.	371	22.6	6/9/1988	
	4,929,889	5/29/1990	Seller, et al.	371	22.3	6/13/1988	
	4,930,216	6/5/1990	Nelson	29	854	3/10/1989	
	4,931,722	6/5/1990	Stoica	371	22.5	11/7/1985	
	4,935,868	6/1/1990	Dulac	364	200	11/28/1988	
	4,937,826	6/26/1990	Gheewala, et al.	371	22.1	9/9/1988	
	4,943,966	7/24/1990	Giunta, et al.	371	11.1	4/8/1988	
	4,945,536	7/31/1990	Hancu	371	22.3	9/9/1988	
	4,947,106	8/7/1990	Chism	324	73.1	3/31/1988	
	4,956,602	9/11/1990	Parrish	324	158 R	2/14/1989	
	4,961,053	10/2/1990	Krug	324	158 R	7/24/1985	
4,969,121	11/6/1990	Chan, et al.	364	900	3/2/1987		
4,974,192	11/27/1990	Face, et al.	364	900	7/23/1987		
CB	4,974,226	11/27/1990	Fujimori, et al.	371	22.3	9/22/1988	
EXAMINER CB				DATE CONSIDERED 4-15-05			
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U.S. PATENT DOCUMENTS

+EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
CB	4,989,209	1/29/1991	Littlebury, et al.	371	22.1	3/24/1989
	4,992,985	2/12/1991	Miyazawa, et al.	365	201	4/22/1987
	5,001,713	3/19/1991	Whetsel	371	22.3	2/8/1989
	5,008,885	4/16/1991	Huang, et al.	371	3	12/29/1988
	5,014,186	5/1/1991	Chisholm	395	850	8/1/1986
	5,023,872	6/11/1991	Annamalai	371	5.1	3/25/1988
	5,042,005	8/20/1991	Miller, et al.	364	900	8/19/1988
	5,051,996	9/24/1991	Bergeson, et al.	371	22.4	3/27/1989
	5,053,949	10/1/1991	Allison, et al.	364	200	4/3/1989
	5,056,094	10/8/1991	Whetsel	371	25.1	6/9/1989
	5,084,814	1/28/1992	Vaglica, et al.	395	325	10/30/1987
	5,084,874	1/28/1992	Whetsel	371	22.3	11/7/1988
	5,128,664	7/1/1992	Bishop	340	825.52	5/5/1986
	5,133,062	7/1/1992	Joshi, et al.	395	500	3/6/1986
	5,155,432	10/13/1992	Mahoney	324	158 R	10/7/1987
	5,159,465	10/1/1992	Maemura, et al.	326	73	10/5/1988
	5,167,020	11/24/1992	Kahn, et al.	395	250	5/25/1989
	5,187,795	2/1/1993	Balmforth, et al.	395	800	1/27/1989
	5,214,760	5/1/1993	Hammond, et al.	395	250	8/26/1988
	5,218,702	6/1/1993	Kirtland	395	298	7/6/1988
	5,276,807	1/1/1994	Kodoma, et al.	395	309	4/13/1987
	5,303,148	4/12/1994	Mattson, et al.	364	413.01	11/27/1987
	5,329,471	7/12/1994	Swoboda, et al.	364	578	6/2/1987
	5,495,487	2/27/1996	Whetsel, Jr.	371	25.1	9/7/1988
	5,602,855	2/11/1997	Whetsel	371	22.3	9/7/1988
CB	5,905,738	3/18/1999	Whetsel	371	22.4	6/19/1989

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FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
LB	EP 0,136,174	4/3/1985	Europe	G06	F9/30	X
	EP 0,148,403	7/17/1985	Europe	G01	R31/28	X
	EP 0,190,494	8/13/1986	Europe	G01	R31/28	X
	EP 0,195,164	9/24/1986	Europe	G01	R31/28	X
	EP 0,273,821	7/6/1988	Europe	G01	R31/28	X
	EP 0,310,152	4/5/1989	Europe	G01	R31/28	X
	JP 01-038674 A	2/8/1989	Japan	G01R	31/28	X
	JP 01-043773	2/16/1989	Japan	G01	R31/28	X
	JP 01-068167 A	3/14/1989	Japan	H04M	3/22	X
	JP 01-110274	4/26/1989	Japan	G01R31	28	X
	JP 57-094857 A	6/12/1982	Japan	G06F	37582	X
	JP 57-209546	12/22/1982	Japan	G06F11	20	X
	JP 58-155599	9/16/1983	Japan	G11	C29	X
	JP 58-191021 A	11/8/1983	Japan	G06F	36586	X
	JP 59-210382	11/29/1984	Japan	G01R31	28	X
	JP 60-140834 A	7/25/1985	Japan	H01L	21/66	X
	JP 60-252958	12/13/1985	Japan	G06F11	22	X
	JP 60-262073	12/25/1985	Japan	G01R	31/28	X
	JP 62-031447 A	2/10/1987	Japan	G06F	37582	X
	JP 62-228177	10/7/1987	Japan	G01R31	28	X
	JP 62-280663	12/5/1987	Japan	G01R	31/28	X
	JP 63-073169	4/2/1988	Japan	G01R31	28	X
	JP 63-188783 A	8/4/1988	Japan	G01R	31/28	X
	JP 63-213014 A	9/5/1988	Japan	G06F	37260	X
	JP 63-310046 A	12/19/1988	Japan	G06F	37606	X
	JP 64-006572	1/13/1989	Japan	G01R	31/28	X
	JP 64-079673(A)	3/24/1989	Japan	G01R31	28	X
LB	WO 88/04097	6/2/1988	PCT	G11	C15/00	X

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CB	Bhavsar, et al., "Self-Testing by Polynomial Division", Digest of Papers, International Test Conference, 1981, pp.208-216	1/1/1981
	Breuer, Melvin A.; Lien, Jung-Cheun, "A Test and Maintenance Controller for a Module Containing Testable Chips", 1988 International Test Conference, Sept. 12-14, 1988, Paper 27.1, pp. 502-513	9/12/1988
	Dervisoglu, Bulent I., "Using Scan Technology for Debug and Diagnostics in a Workstation Environment", 1988 International Test Conference, Sept. 12-14, 1988, Paper 45.2, pp.976-986	9/12/1988
	El-ziq, et al., "A Mixed-Mode Built-In Self-Test Technique Using Scan Path and Signature Analysis", International Test Conference, Oct. 18-20, 1983, pp. 269-274	10/18/1983
	ETM-Bus Specification, VHSIC Phase 2 Interoperability Standards, December 31, 1985, Version 1.0	12/31/1985
	Haedtke, et al., "Multilevel Self-test for the Factory and Field", Proceedings, Annual Reliability and Maintainability Symposium, 1987	1/1/1987
	Hahn, et al., "VLSI Testing By On-Chip Error Detection", IBM Technical Disclosure Bulletin, Vol. 25, No. 2, July 1982	7/1/1982
	Hudson, et al., "Parallel Self-test With Pseudo-Random Test Patterns", International Test Conference, Sept. 1-3, 1987, pp.954-963	9/1/1987
	Hudson, et al., "Integrating BIST And Boundary-Scan On A Board", Proceedings of the National Communications Forum, Sept. 30, 1988, pp. 1796-1800	9/30/1988
	IBM Technical Disclosure Bulletin, "Bidirectional Double Latch", Vol. 28, No. 1, June, 1985	6/1/1985
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LIST OF DOCUMENTS CITED BY APPLICANT <i>(Use several sheets if necessary)</i>				APPLICANT Lee D. Whetsel	
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